

Search Notes

Application/Control No.

10/689,721

Examiner

Alex Liew

Applicant(s)/Patent under
Reexamination

BAN ET AL.

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner
382	153	2/23/2007	AL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/154 limited to text search	2/23/2007	AL
382/106,153,154 limited to text search	12/19/2007	AL